

<b>Notice of References Cited</b>	Application/Control No. 09/932,086	Applicant(s)/Patent Under Reexamination FARKAS ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NN74091034: "Circuit Diagnosis and Design Analysis System; IBM Tech. Discl. Bulletin, July 1987, US, VOL. 17 ISSUE: 4 Figs. 1034 - 1035 ; September 1, 1974 "
	V	Abramovici et al. "Digital Systems Testing and Testable Design," 1990, pgs. 479-487
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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